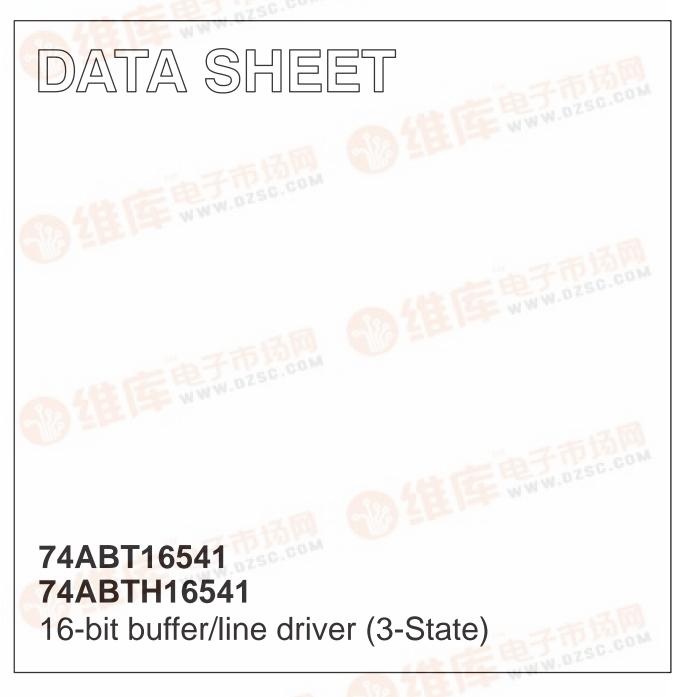
### INTEGRATED CIRCUITSPCB打样工厂, 24小时加



Product specification Supersedes data of 1995 Sep 18 IC23 Data Handbook 1998 Feb 25







### 74ABT16541 74ABTH16541

#### **FEATURES**

- Power-up 3-State
- Multiple V<sub>CC</sub> and GND pins minimize switching noise
- Provides ideal interface and increases fan-out of MOS Microprocessors
- 3-State buffers sink 64mA and source 32mA
- 74ABTH16541 incorporates bus-hold data inputs which eliminate the need for external pull-up resistors to hold unused inputs
- Latch-up protection exceeds 500mA per Jedec Std 17
- ESD protection exceeds 2000 V per MIL STD 883 Method 3015 and 200 V per Machine Model
- Two 8-bit bus interfaces
- Bus-hold data inputs eliminate the need for external pull-up resistors to hold unused inputs

#### QUICK REFERENCE DATA

#### DESCRIPTION

The 74ABT16541 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74ABT16541 has two octal buffers that are ideal for driving bus lines. The outputs are all capable of sinking 64mA and sourcing 32mA.

Two options are available, 74ABT16541 which does not have the bus-hold feature and 74ABTH16541 which incorporates the bus-hold feature.

SYMBOL	PARAMETER	CONDITIONS T <sub>amb</sub> = 25°C; GND = 0V	TYPICAL	UNIT
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay nAx to nYx	$C_{L} = 50 pF; V_{CC} = 5V$	2.0 1.5	ns
C <sub>IN</sub>	Input capacitance	$V_I = 0V \text{ or } V_{CC}$	4	pF
C <sub>OUT</sub>	Output capacitance	$V_{O} = 0V \text{ or } V_{CC}; 3\text{-State}$	6	pF
I <sub>CCZ</sub>		Outputs disabled; $V_{CC}$ =5.5V	500	μΑ
I <sub>CCL</sub>	Quiescent supply current	Outputs LOW; $V_{CC} = 5.5V$	8	mA

#### **ORDERING INFORMATION**

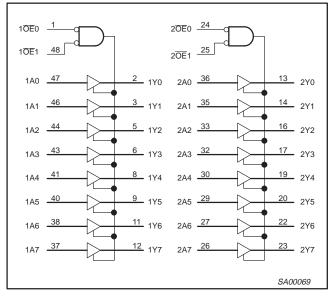
PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
48-Pin Plastic SSOP Type III	–40°C to +85°C	74ABT16541 DL	BT16541 DL	SOT370-1
48-Pin Plastic TSSOP Type II	–40°C to +85°C	74ABT16541 DGG	BT16541 DGG	SOT362-1
48-Pin Plastic SSOP Type III	–40°C to +85°C	74ABTH16541 DL	BH16541 DL	SOT370-1
48-Pin Plastic TSSOP Type II	–40°C to +85°C	74ABTH16541 DGG	BH16541 DGG	SOT362-1

### **PIN DESCRIPTION**

PIN NUMBER	SYMBOL	NAME AND FUNCTION
47, 46, 44, 43, 41, 40, 38, 37, 36, 35, 33, 32, 30, 29, 27, 26	1A0 - 1A7 2A0 - 2A7	Data inputs
2, 3, 5, 6, 8, 9, 11, 12, 13, 14, 16, 17 19, 20, 22, 23	1Y0 - 1Y7, 2Y0 - 2Y7	Data outputs
1, 48 24, 25	10E0, 10E1, 20E0, 20E1	Output enables
4, 10, 15, 21 28, 34, 39, 45	GND	Ground (0V)
7, 18, 31, 42	V <sub>CC</sub>	Positive supply voltage

### 74ABT16541 74ABTH16541

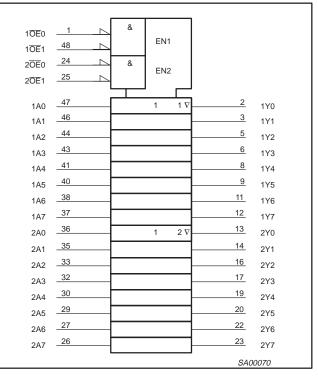
### LOGIC SYMBOL



#### **PIN CONFIGURATION**

1 <del>0E</del> 0		48	1 <del>0E</del> 1
1Y0	2	47	1A0
1Y1	3	46	1A1
GND	4	45	GND
1Y2	5	44	1A2
1Y3			1A3
	6	43	
VCC	7	42	VCC
1Y4	8	41	1A4
1Y5	9	40	1A5
GND	10	39	GND
1Y6	11	38	1A6
1Y7	12	37	1A7
2Y0	13	36	2A0
2Y1	14	35	2A1
GND	15	34	GND
2Y2	16	33	2A2
2Y3	17	32	2A3
VCC	18	31	VCC
2Y4	19	30	2A4
2Y5	20	29	2A5
GND	21	28	GND
2Y6	22	27	2A6
2Y7	23	26	2A7
2 <del>0E</del> 0	24	25	2 <del>0E</del> 1
		]	22222
		SA	00068

#### LOGIC SYMBOL (IEEE/IEC)



#### **FUNCTION TABLE**

	OUTPUTS		
n <mark>OE</mark> 0	n <mark>OE</mark> 1	nlx	nYx
L	L	L	L
L	L	н	н
х	н	х	Z
н	х	х	Z

H = HIGH voltage level

L = LOW voltage level

X = D0n't care Z = High impedance "off" state

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#### ABSOLUTE MAXIMUM RATINGS<sup>1, 2</sup>

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V <sub>CC</sub>	DC supply voltage		-0.5 to +7.0	V
I <sub>IK</sub>	DC input diode current	V <sub>1</sub> < 0	-18	mA
VI	DC input voltage <sup>3</sup>		-1.2 to +7.0	V
I <sub>ОК</sub>	DC output diode current	V <sub>O</sub> < 0	-50	mA
V <sub>OUT</sub>	DC output voltage <sup>3</sup>	output in Off or High state	–0.5 to +5.5	V
I <sub>OUT</sub>	DC output current	output in Low state	128	mA
T <sub>stg</sub>	Storage temperature range		-65 to 150	°C

NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

 The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.

3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

#### **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER	LIM	ITS	UNIT	
STWBOL	PARAMETER	Min	Max	UNIT	
V <sub>CC</sub>	DC supply voltage	4.5	5.5	V	
VI	Input voltage	0	V <sub>CC</sub>	V	
V <sub>IH</sub>	High-level input voltage	2.0		V	
V <sub>IL</sub>	Low-level Input voltage		0.8	V	
I <sub>ОН</sub>	High-level output current		-32	mA	
I <sub>OL</sub>	Low-level output current		64	mA	
Δt/Δv	Input transition rise or fall rate	0	10	ns/V	
T <sub>amb</sub>	Operating free-air temperature range	-40	+85	°C	

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### DC ELECTRICAL CHARACTERISTICS

						LIMITS			
SYMBOL	PARAMETER	TEST CONDITION	S	T <sub>amb</sub> = +25°C		°C	T <sub>amb</sub> = −40°C to +85°C		
			Min		Тур	Max	Min	Max	
VIK	Input clamp voltage	V <sub>CC</sub> = 4.5V; I <sub>IK</sub> = -18mA			-0.9	-1.2		-1.2	V
		$V_{CC} = 4.5V; I_{OH} = -3mA; V_{I} = V$	′ <sub>IL</sub> or V <sub>IH</sub>	2.5	2.9		2.5		V
V <sub>OH</sub>	High-level output voltage	$V_{CC} = 5.0V; I_{OH} = -3mA; V_{I} = V$	′ <sub>IL</sub> or V <sub>IH</sub>	3.0	3.4		3.0		V
		$V_{CC}$ = 4.5V; $I_{OH}$ = –32mA; $V_{I}$ =	V <sub>IL</sub> or V <sub>IH</sub>	2.0	2.4		2.0		V
V <sub>OL</sub>	Low-level output voltage	$V_{CC} = 4.5$ V; $I_{OL} = 64$ mA; $V_{I} = V$	<sub>IL</sub> or V <sub>IH</sub>		0.42	0.55		0.55	V
I	Input leakage current	$V_{CC}$ = 5.5V; $V_{I}$ = GND or 5.5V			±0.01	±1.0		±1.0	μΑ
	Input leakage current	$V_{CC}$ = 5.5V; $V_{I}$ = $V_{CC}$ or GND	Control pins		±0.01	±1		±1	μΑ
I	74ABTH16541	$V_{CC} = 5.5 V; V_{I} = V_{CC}$	Data pins		0.01	1		1	μΑ
		$V_{CC} = 5.5 V; V_{I} = 0$	$V_{CC} = 5.5V; V_I = 0$		-2	-3		-5	μΑ
	Due Held summert A insute3	$V_{CC} = 4.5V; V_I = 0.8V$ $V_{CC} = 4.5V; V_I = 2.0V$		50			50		
I <sub>HOLD</sub>	Bus Hold current A inputs <sup>3</sup> 74ABTH16541			-75			-75		μA
		$V_{CC} = 5.5V; V_{I} = 0 \text{ to } 5.5V$		±500					
I <sub>OFF</sub>	Power-off leakage current	$V_{CC}$ = 0.0V; $V_O$ or $V_I \leq 4.5V$			±5.0	±100		±100	μA
I <sub>PU</sub> /I <sub>PD</sub>	Power-up/down 3-State output current	$V_{\underline{CC}} = 2.0V; V_{\underline{O}} = 0.5V; V_{\underline{I}} = GN$ $V_{\underline{OE}} = V_{\underline{CC}}$	ID or V <sub>CC</sub> ;		±5.0	±50		±50	μΑ
I <sub>OZH</sub>	3-State output High current	$V_{CC} = 5.5 V; V_{O} = 2.7 V; V_{I} = V_{IL}$	or V <sub>IH</sub>		1.0	10		10	μΑ
I <sub>OZL</sub>	3-State output Low current	$V_{CC} = 5.5$ V; $V_{O} = 0.5$ V; $V_{I} = V_{IL}$	or V <sub>IH</sub>		-1.0	-10		-10	μΑ
I <sub>CEX</sub>	Output high leakage current	$V_{CC} = 5.5$ V; $V_{O} = 5.5$ V; $V_{I} = GN$	ID or V <sub>CC</sub>		1.0	50		50	μΑ
Ι <sub>Ο</sub>	Output current <sup>1</sup>	$V_{CC} = 5.5 V; V_{O} = 2.5 V$		-50	-70	-180	-50	-180	mA
I <sub>CCH</sub>		$V_{CC}$ = 5.5V; Outputs High, V <sub>I</sub> =	GND or V <sub>CC</sub>		0.5	1.0		1.0	mA
I <sub>CCL</sub>	Quiescent supply current	$V_{CC}$ = 5.5V; Outputs Low, $V_{I}$ = GND or $V_{CC}$			8	19		19	mA
I <sub>CCZ</sub>		$V_{CC}$ = 5.5V; Outputs 3-State; V <sub>I</sub> = GND or V <sub>CC</sub>			0.5	1.0		1.0	mA
$\Delta I_{CC}$	Additional supply current per input pin <sup>2</sup> 74ABT16541	Outputs enabled, one input at 3 inputs at $V_{CC}$ or GND; $V_{CC}$ = 5.			100	250		250	μA
$\Delta I_{CC}$	Additional supply current per input pin <sup>2</sup> 74ABTH16541	Outputs enabled, one input at 3 inputs at $V_{CC}$ or GND; $V_{CC}$ = 5.			0.2	1.0		1.0	mA

NOTES:

1. Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

2. This is the increase in supply current for each input at 3.4V.

3. This is the bus hold overdrive current required to force the input to the opposite logic state.

### **AC CHARACTERISTICS**

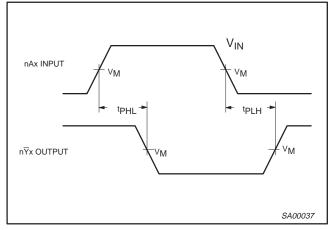
GND = 0V;  $t_R$  =  $t_F$  = 2.5ns;  $C_L$  = 50pF,  $R_L$  = 500 $\Omega$ 

					LIMI	rs		
SYMBOL	PARAMETER	WAVEFORM	T <sub>2</sub> V	amb = +25° ′ <sub>CC</sub> = +5.0′	C V	$T_{amb} = -40^{\circ}$ $V_{CC} = +5^{\circ}$	°C to +85°C 0V ±0.5V	UNIT
			Min	Тур	Мах	Min	Мах	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay nlx to nYx	1	1.0 1.0	2.0 1.5	3.0 3.6	1.0 1.0	3.4 4.2	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output enable time to High and Low level	2	1.3 1.6	2.9 3.1	4.3 4.7	1.3 1.6	5.2 6.0	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output disable time from High and Low level	2	1.3 1.0	3.5 2.8	4.4 3.6	1.3 1.0	5.1 3.9	ns

### 74ABT16541 74ABTH16541

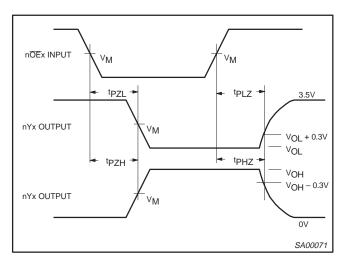
#### AC WAVEFORMS

 $V_M = 1.5V$ ,  $V_{IN} = GND$  to 3.0V



Waveform 1. Input (An) to Output (Yn) Propagation Delays

**TEST CIRCUIT AND WAVEFORMS** 



Waveform 2. 3-State Output Enable and Disable Times

#### VCC tw AMP (V) 90% 90% -0 7.0V NEGATIVE PULSE ٧N ٧M 10% 10% RL 0V VIN VOUT PULSE D.U.T. tTHL (tF) GENERATOR tTLH (tR) tTHL (tF) tTLH (tR) Rт Сі RL AMP (V) 90% 90% POSITIVE PULSE ٧M ٧M **Test Circuit for 3-State Outputs** 10% 10% 0V tw **SWITCH POSITION** $V_{M} = 1.5V$ **Input Pulse Definition**

TEST	SWITCH
t <sub>PLZ</sub>	closed
t <sub>PZL</sub>	closed
All other	open

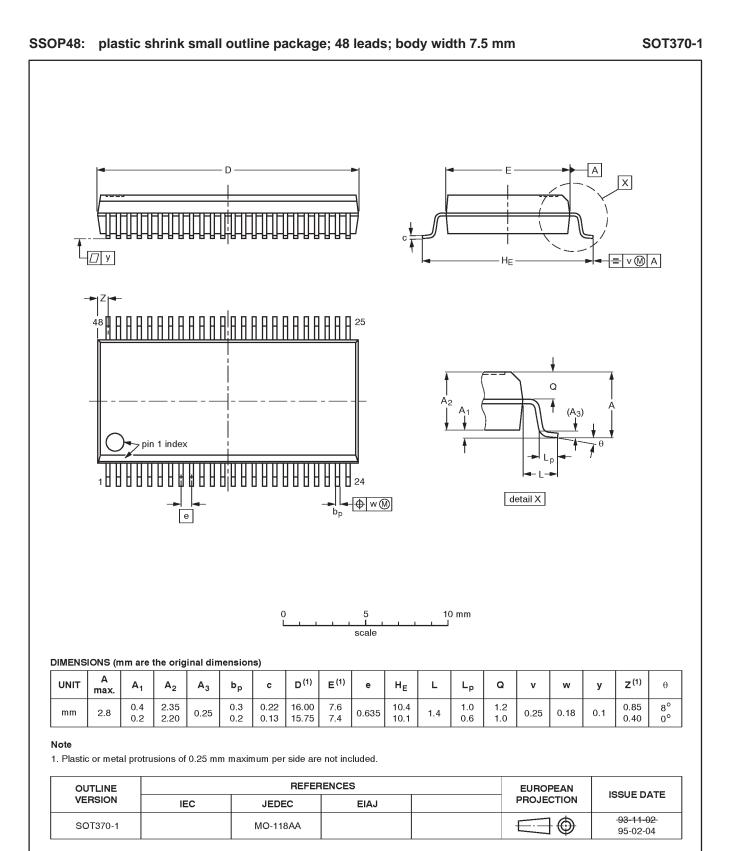
#### DEFINITIONS

- $R_L$  = Load resistor; see AC CHARACTERISTICS for value.
- $\label{eq:CL} \begin{array}{ll} \mathsf{C}_{\mathsf{L}} = & \mathsf{Load} \mbox{ capacitance includes jig and probe capacitance;} \\ & \mathsf{see} \mbox{ AC CHARACTERISTICS for value.} \end{array}$
- $R_T$  = Termination resistance should be equal to  $Z_{OUT}$  of pulse generators.

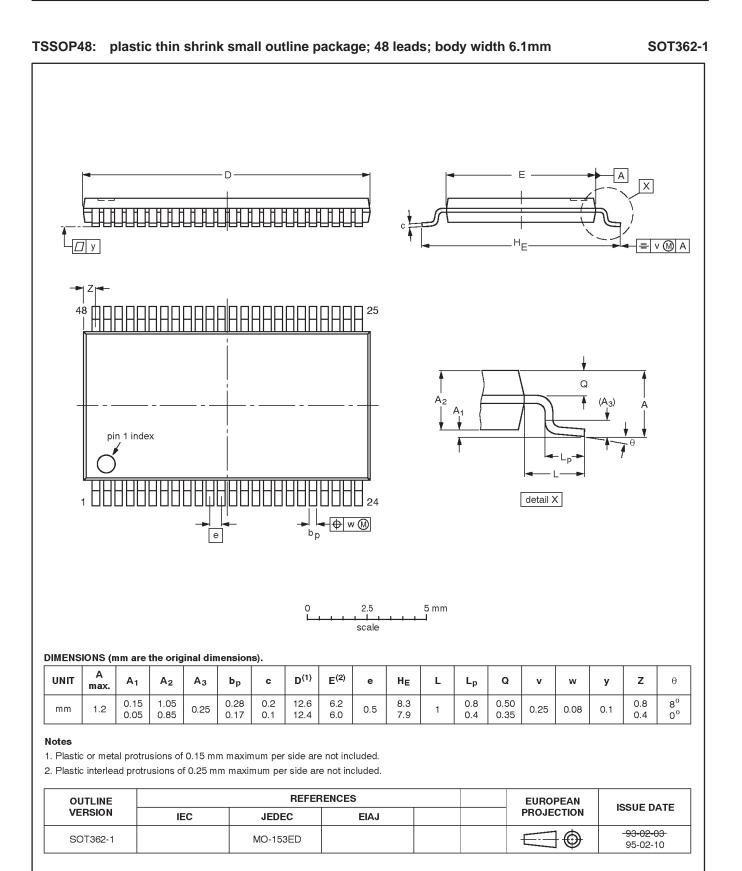
	INPUT PULSE REQUIREMENTS						
FAMILY	Amplitude	Rep. Rate	t <sub>W</sub>	t <sub>R</sub>	t <sub>F</sub>		
74ABT	3.0V	1MHz	500ns	2.5ns	2.5ns		

SA00012

### 74ABT16541 74ABTH16541



### 74ABT16541 74ABTH16541



Product specification

# 16-bit buffer/line driver (3-State)

### 74ABT16541 74ABTH16541

NOTES

### 74ABT16541 74ABTH16541

#### Data sheet status

Data sheet status	Product status	Definition <sup>[1]</sup>
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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print code Document order number: Date of release: 05-96 9397-750-03495

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